

touch, test, invent®

...With the next generation current and voltage source/measure instruments from Keithley!

The advantage of a touchscreen interface lies in helping you get to your test results quickly and with the high degree of accuracy you'd expect from a Keithley source/measure instrument. These touchscreen instruments enable:

- Intuitive user interface minimizes your learning curve
- Easy navigation between setup and configuration menus means fewer errors
- Real time graphing & data visualization get you to your answer faster

Touchscreen Source Measure Units



	General Purpose (Up to 1A)	High Current (>1A)			
Model	<u>2450</u>	2460 1pA - 7A 100nV - 100V			
Current Range	10fA – 1A				
Voltage Range	10nV – 200V				
Power	20W	100W			
Price	\$5,400	\$7,500			

Get more info on the Model 2450 and Model 2460 touchscreen SMUs.

Non-Touchscreen Source Measure Units



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Model	2400	<u>2401</u>	2410	<u>6430</u>	2420	2425	2430	<u>2440</u>	
Current Range	Up to 1A Up to 1 kV 20W			As low as 10aA	up to 5A DC, 10A Pulse (2430)				
Voltage Range				1µV – 200V	1uV – 100V				
Power				2W	60W 100W 1000W Pulse			50W	
Price	\$4,720	\$3,470	\$6,750	\$14,300	\$6,760	\$8,050	\$11,800	\$7,690	

For System Level Testing Use IVy And Continue the Touchscreen Journey with 2600B SourceMeter Units

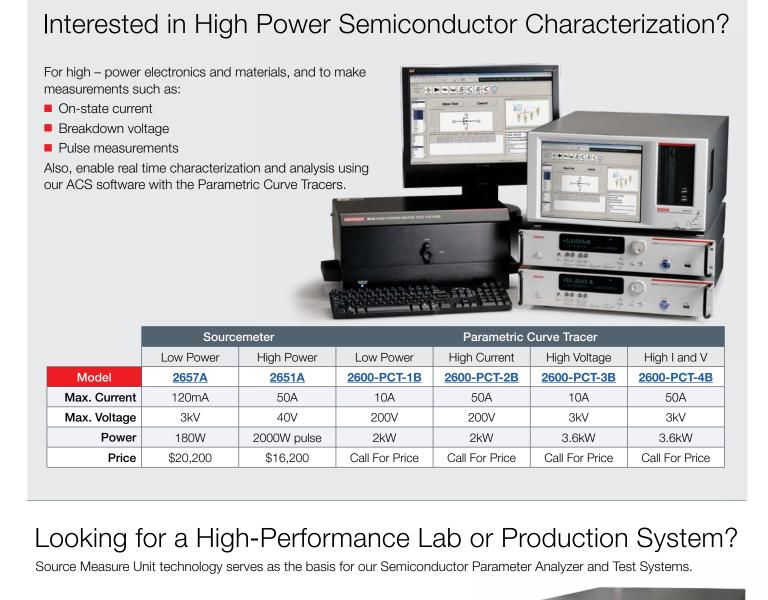


technology providing 10x the throughput over PC/GPIB control, leading to a complete measurement and automation solution.

Single Channel

Dual Channel

	Model	<u>2601B</u>	<u>2611B</u>	<u>2635B</u>	<u>2602B</u>	<u>2604B</u>	<u>2612B</u>	<u>2614B</u>	<u>2634B</u>	<u>2636B</u>
	Power	40W/30W		30W	40W/channel		30W/channel		30W/channel	
	Current Range	Up to 3A DC		0.1fA – 1.5A DC	Up to 3A DC		100fA – 1.5A DC		0.1fA – 1.5A DC	
	Voltage Range	Up to	200V	100nV-200V	V 100nV-40V		100nV-200V		100nV-200V	
	Price	Price \$6,650		\$9,910	\$9,760	\$8,090	\$9,760	\$8,090	\$12,700	\$15,300
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An All-In-One Characterization Analyzer: Model 4200-SCS For electrical characterization of materials, semiconductor devices and

to perform C-V or I-V measurements, including ultra-fast pulsed and transient I-V.

Semiconductor Wafer/Device Test: S530 and S500 Systems:

In production or the lab, <u>\$530 Parametric Test Systems</u> can be flexibly applied across many devices, making it easy to adapt it for varying test plan, automation, data management, and probe station requirements.

For semiconductor characterization at the device, wafer,

processes consider the 4200-SCS, a fully integrated parameter analyzer. Use it

or cassette level, <u>S500 Integrated Test Systems</u> offer special capabilities such as pulse generation and ultrafast IV for memory characterization, charge pumping, and powerful and flexible ACS software. High-voltage, current and power source measure units are part of the instrumentation.

